



BSI Standards Publication

Test methods for electrical materials, printed board and other interconnection structures and assemblies

Part 5-503: General test method for materials and assemblies – Conductive anodic filaments (CAF) testing of circuit boards (IEC 61189-5-503:2017)

National foreword

This British Standard is the UK implementation of EN 61189-5-503:2017. It is identical to IEC 61189-5-503:2017.

The UK participation in its preparation was entrusted to Technical Committee EPL/501, Electronic Assembly Technology.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Date	Text affected
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English Version

**Test methods for electrical materials, printed board and other
interconnection structures and assemblies - Part 5-503: General
test method for materials and assemblies - Conductive anodic
filaments (CAF) testing of circuit boards
(IEC 61189-5-503:2017)**

Méthodes d'essai pour les matériaux électriques, les cartes
imprimées et autres structures d'interconnexion et
ensembles - Partie 5-503 : Méthodes d'essai générales
pour les matériaux et les assemblages - Essais des
filaments anodiques conducteurs (CAF) des cartes à circuit
imprimé
(IEC 61189-5-503:2017)

Prüfverfahren für Elektromaterialien, Leiterplatten und
andere Verbindungsstrukturen und Baugruppen - Teil 5-
503: Allgemeine Prüfverfahren für Materialien und
Baugruppen - Leitfähige anodische Fasern (CAF), Prüfung
für Leiterplatten
(IEC 61189-5-503:2017)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

European foreword

The text of document 91/1433/FDIS, future edition 1 of IEC 61189-5-503, prepared by IEC/TC 91 "Electronics assembly technology" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61189-5-503:2017.

The following dates are fixed:

- latest date by which the document has to be (dop) 2018-03-26
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publication of an identical national
standard or by endorsement
- latest date by which the national (dow) 2020-06-26
standards conflicting with the
document have to be withdrawn

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60068-3-4	NOTE	Harmonized as EN 60068-3-4.
IEC 60068-3-5	NOTE	Harmonized as EN 60068-3-5.
IEC 60721-1	NOTE	Harmonized as EN 60721-1.
IEC 60721-2-1	NOTE	Harmonized as EN 60721-2-1.
IEC 60721-3-0	NOTE	Harmonized as EN 60721-3-0.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-1	2013	Environmental testing -- Part 1: General and guidance	EN 60068-1	2014
IEC 60068-2-30	-	Environmental testing -- Part 2-30: Tests - Test Db: Damp heat, cyclic (12 h + 12 h cycle)	EN 60068-2-30	-
IEC 60068-2-38	-	Environmental testing -- Part 2-38: Tests - Test Z/AD: Composite temperature/humidity cyclic test	EN 60068-2-38	-
IEC 60068-2-66	-	Environmental testing -- Part 2-66: Test methods - Test Cx: Damp heat, steady state (unsaturated pressurized vapour)	EN 60068-2-66	-
IEC 60068-2-67	-	Environmental testing -- Part 2: Tests - Test Cy: Damp heat, steady state, accelerated test primarily intended for components	EN 60068-2-67	-
IEC 60068-2-78	-	Environmental testing -- Part 2-78: Tests - Test Cab: Damp heat, steady state	EN 60068-2-78	-
IEC 60194	-	Printed board design, manufacture and assembly - Terms and definitions	-	-
IPC-TM-650 No 2.6.14.1	-	Electrochemical Migration Resistance Test	-	-
IPC-TM-650 No 2.6.25	-	Conductive Anodic Filament (CAF) Resistance Test: X-Y Axis	-	-

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**TEST METHODS FOR ELECTRICAL MATERIALS, PRINTED BOARD
AND OTHER INTERCONNECTION STRUCTURES AND ASSEMBLIES –****Part 5-503: General test method for materials and assemblies –
Conductive anodic filaments (CAF) testing of circuit boards**

FOREWORD

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International Standard IEC 61189-5-503 been prepared by IEC technical committee 91: Electronics assembly technology.

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91/1433/FDIS	91/1443/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.